

Attorney Docket No. 04083/LH

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Takashi YONEYAMA, et al.

Serial No. : 10/773,524

Confirm. No.: 7190

Filed : February 6, 2004

For : DEFECT INSPECTION APPARATUS AND
DEFECT INSPECTION METHOD

Art Unit : 2624

Examiner : Tsung Yin Tsai

STATEMENT OF SUBSTANCE OF INTERVIEW

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

This Statement of Substance of Interview is being filed to record the substance of a telephone interview between the Examiner and the undersigned on April 22, 2008. This Statement is being timely filed within one month of the interview.

SUBSTANCE OF INTERVIEW

As set forth in the Interview Summary, independent claim 9 and USP 5,761,336 ("Xu et al") were discussed in the telephone interview. More specifically, amending claim 9 to more explicitly define the "sample information" was discussed. No specific agreement with respect to patentability was reached.

This paper is being submitted via EFS-Web on May 5, 2008

In the event that this Paper is late filed, and the necessary petition for extension of time is not filed concurrently herewith, please consider this as a Petition for the requisite extension of time, and to the extent not already paid, authorization to charge the extension fee to Account No. 06-1378. In addition, authorization is hereby given to charge any fees for which payment has not been submitted, or to credit any overpayments, to Account No. 06-1378.

In the Amendment filed on April 28, 2008, the claims were amended based on the telephone interview.

If the Examiner has any comments, questions, objections or recommendations, the Examiner is invited to telephone the undersigned for prompt action.

Respectfully submitted,

/Douglas Holtz/

Douglas Holtz
Reg. No. 33,902

Frishauf, Holtz, Goodman & Chick, P.C.
220 Fifth Avenue - 16th Floor
New York, New York 10001-7708
Tel. No. (212) 319-4900
DH:iv